

**In the Claims:**

Please amend claims 3, 5, 7 16, 17, 19, 21, 31 and 32. Please cancel claims 14, 33-36

The claims are as follows:

1. (Canceled)
2. (Previously Presented) The computer system of claim 31, wherein said simulated external memory mapped test device and said simulated switch are distributed among a plurality of simulated external memory mapped test device modules, each module of said plurality of simulated external memory mapped test device modules containing a portion of said simulated switch and connected to a respective second external I/O driver model of said second external I/O driver models.
3. (Currently Amended) The computer system of claim 31, wherein said simulated external memory mapped test device further includes a simulated address register.
4. (Canceled)
5. (Currently Amended) The computer system of claim 2, wherein each said simulated external memory mapped test device module further includes a simulated address register.
6. (Canceled)

7. (Currently Amended) The computer system of claim 31, wherein said simulated external memory mapped test device and said simulated switch are distributed among a plurality of simulated external memory mapped test device modules, each module of said plurality of simulated external memory mapped test device modules containing a portion of said simulated switch and connected to a respective second external I/O driver model of said one or more second external I/O driver models; and

~~further including the method steps of~~ executing said instructions causes the computer to perform the further following steps:

loading code representing an additional simulated external memory mapped test device module into said memory unit;

said loading of said test case connecting one or more additional second external I/O driver models to said additional simulated external memory mapped test device by additional simulated I/O buses; and

said loading of said test case connecting each additional second external I/O driver model to a respective additional simulated I/O core by said simulated system bus, each additional simulated I/O core comprising said model of integrated circuit design.

8-15 (Canceled)

16. (Currently Amended) The ~~computer program storage device~~ product of claim 32, ~~said method steps further including: distributing wherein~~ said simulated external memory mapped test device and said simulated switch are distributed among a plurality of simulated external memory mapped test device modules, each module of said plurality of simulated external memory

modules containing a portion of said simulated switch and connected to one of said simulated I/O driver models.

17. (Currently Amended) The ~~computer program storage device product~~ of claim 32, ~~said method steps further including: providing wherein~~ said simulated external memory mapped test device ~~with~~ includes a simulated address register; and

executing said instructions, further causes said computer to connect setting said simulated switch ~~and controlling control said simulated~~ to one second external I/O driver model of said one or more second external I/O driver models using address information programmed into said simulated address register.

18. (Canceled)

19. (Currently Amended) The ~~computer program storage device product~~ of claim 16, ~~said method steps further including: providing wherein~~ each simulated external memory mapped test device ~~with~~ includes a corresponding simulated address register; and

executing said instructions, further causes said computer to connect setting each portion of said simulated switch ~~and controlling control each simulated~~ to one second external I/O driver model of said one or more I/O driver models using address information programmed into its corresponding said simulated address register.

20. (Canceled)

21. (Currently amended) The computer system of claim 31, wherein said one or more simulated I/O cores ~~includes~~ are each independently selected from the group consisting of a simulated 1394 I/O core, a simulated universal asynchronous receiver transmitter core, a simulated serial core[[s]], a simulated general purpose I/O core, and a direct memory access core ~~or combinations thereof~~.

22 -30 (Canceled)

31. (Currently Amended) A computer system comprising a processor and a computer-readable memory unit coupled to communicate with said processor, said memory unit containing instructions that when executed by the processor ~~implement a method for verifying an integrated circuit design, said method comprising the computer implemented steps of~~ causes the computer to perform the following steps:

loading code representing said integrated circuit design into said memory unit, said integrated circuit design including simulated I/O cores, a simulated ~~external~~ memory controller, a simulated I/O controller, a simulated bus system and a simulated processor, said simulated I/O cores and said simulated I/O controller connected to said simulated processor by said simulated system bus;

loading into said memory unit, code representing (i) an external memory model[[,]] connected to a simulated external memory mapped test device and to said simulated memory controller, (ii) one or more first external I/O driver models ~~into said memory unit connected between said simulated I/O cores and said simulated external memory mapped test device and~~ (iii) one or more second external I/O driver models connected between a simulated switch of said

simulated external memory mapped test device and said I/O controller, said simulated external memory mapped test device including a simulated switch programmably connectable to said one or more second external I/O driver models in response to computer-executable instructions in a test case, to said simulated I/O controller and to said external memory model, said I/O driver models connected to corresponding said simulated I/O cores by, all said connections of (i), (ii) and (iii) by corresponding simulated I/O buses;

loading ~~[[a]]~~ said test case, said test case comprising ~~[[a]]~~ said list of computer-executable instructions ~~[[on]]~~ for said simulated processor into said external memory model, said instructions describing selection of one or more simulated I/O cores and corresponding second external I/O models, allocation of pins of said I/O controller to selected simulated I/O cores and switch positions of said simulated switch to connect said corresponding second external I/O models to said I/O controller~~[[.]]~~:

~~said loading of executing~~ said test case and allocating and connecting I/O pins of said simulated I/O controller to one or more of said simulated I/O cores, and connecting said simulated external memory mapped test device to said simulated I/O controller through said corresponding second external I/O models and to said one or more of said simulated I/O cores;

executing test stimuli of said test case on said simulated processor in order to generate data representing a response of said computer simulation model of said integrated circuit design to said test case; and

outputting said data representing a response of said computer simulation model of said integrated circuit design to said test case to another computer readable media or another computer, (ii) display said data representing a response of said computer simulation model of said integrated circuit design on a computer screen, or both (i) and (ii).

32. (Previously presented) A computer program storage device readable by machine, tangibly embodying a program of instructions executable by machine to perform method steps a method for verifying an integrated circuit design, said method steps comprising product embodied on a computer readable medium comprising code that, when executed, causes a computer to perform the following:

generating load a model of said integrated circuit design into a memory of said computer, said integrated circuit design including simulated I/O cores including a simulated general purpose core, a simulated external memory controller, a simulated I/O controller, a simulated bus system and a simulated processor, said simulated I/O cores and said simulated I/O controller connected to said simulated processor by said simulated system bus;

loading load into said memory unit, code representing (i) an external memory model[[,]] connected to a simulated external memory mapped test device and to said simulated memory controller, (ii) one or more first external I/O driver models into said memory unit connected between said simulated I/O cores and said simulated external memory mapped test device and (iii) one or more second external I/O driver models connected between a simulated switch of said simulated external memory mapped test device and said I/O controller, said ~~simulated external memory mapped test device~~ including a simulated switch programmably connectable to said one or more second external I/O driver models in response to computer-executable instructions in a test case, to said simulated I/O controller and to said external memory model, said I/O driver models connected to corresponding said simulated I/O cores by, all said connections of (i), (ii) and (iii) by corresponding simulated I/O buses;

~~loading a load~~ said test case, said test case comprising [[a]] said list of computer-executable instructions [[on]] for said simulated processor into said external memory model, said instructions describing selection of one or more simulated I/O cores and corresponding second external I/O models, allocation of pins of said I/O controller to selected simulated I/O cores and switch positions of said simulated switch to connect said corresponding second external I/O models to said I/O controller[[,]];

~~said loading of~~ executing said test case and allocating and connecting I/O pins of said simulated I/O controller to one or more of said simulated I/O cores, and connecting said simulated external memory mapped test device to said simulated I/O controller through said corresponding second external I/O models and to said one or more of said simulated I/O cores;  
~~and~~

~~execute~~ executing test stimuli of said test case on said simulated processor;

~~in order to~~ generate data representing a response of said computer simulation model of said integrated circuit design to said test case; and

(i) output said data representing a response of said computer simulation model of said integrated circuit design to said test case to another computer readable media or another computer, (ii) display said data representing a response of said computer simulation model of said integrated circuit design on a computer screen, or both (i) and (ii).

33-36 (Canceled)